Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 108272.01			APPLICATION NO. Rule 53(b) Continuing Application of U.S.			
INFORMATION DISCLOSURE STATEMENT							Appli	cation No. (9/748,207	
(Use several sheets if necessary)					APPLICANT(S) Yoshitaka SASAKI et al.					
					FILING DATE March 2, 2004					
U.S. PATENT DOCUMENTS										
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	ME		CLASS	SUB CLASS	
ДC	1	6,083,410	07/2000		Ikegawa et al.					
Ac	2	6,333,841	12/2001		Sasaki				·	
AC	3	6,459,551	10/2002		Hayakawa					
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FOREIGN PATENT DOCUMENTS										
		DOCUMENT NUMBER	DATE		COUNTRY			CLASS	SUB CLASS	
Ac	4	JP A 4-232250	08/1992		Japan					
AC	5	JP A 9-91618	04/1997		Japan					
K	6	JP A 11-353616	12/1999		Japan					
æ	7	JP A 11-39614	12/1999		Japan			Į		
AC	8	WO 99/41739	08/	1999	WIPO					
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)										
まン		Ericsson et al.; "Properties of Al ₂ O ₂ -films deposited on silicon by atomic layer epitaxy"; Microelectronic Engineering 36 (1997) 91-94								
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EXAMINER	EXAMINER Allun lus DATE CONSIDERED 1/30/0									
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw tine through citation if not in conformance and not considered, belode conv. of this form with next communication to applicant.										

Date: March 2, 2004